

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10590899	FUKUMATSU ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Dawn Garrett	1794

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	(see EAST search history printout for details)	3/16/2009	DG

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Inventor Name Search	3/16/2009	DG
EAST search (see search history printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	3/16/2009	DG
EIC 1700 STIC structure search (see attached printout)	3/10/2009	DG
updated EAST search (see search history printout attached); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	8/28/2009	DG
updated inventor name search	2/9/2010	DG
updated EAST search (see search history printout attached); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	2/9/2010	DG

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	Interference search performed using EAST; Databases: UPAD, USPAT, USPGPUB; keywords searched in claim field (see attached Interference Search history printout)	2/9/2010	DG

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